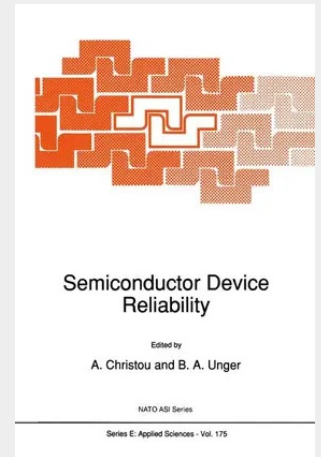


Semiconductor Device Reliability

This publication is a compilation of papers presented at the Semiconductor Device Reliability Workshop sponsored by the NATO International Scientific Exchange Program. The Workshop was held in Crete, Greece from June 4 to June 9, 1989. The objective of the Workshop was to review and to further explore advances in the field of semiconductor reliability through invited paper presentations and discussions. The technical emphasis was on quality assurance and reliability of optoelectronic and high speed semiconductor devices. The primary support for the meeting was provided by the Scientific Affairs Division of NATO. We are indebted to NATO for their support and to Dr. Craig Sinclair, who administers this program. The chapters of this book follow the format and order of the sessions of the meeting. Thirty-six papers were presented and discussed during the five-day Workshop. In addition, two panel sessions were held, with audience participation, where the particularly controversial topics of burn-in and reliability modeling and prediction methods were discussed. A brief review of these sessions is presented in this book.

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